



2025 International Workshop Series on E-waste Statistics (Kenya)



: 8 4 2025

📅 :	Workshop
📍 :	Nairobi, Kenya
📅 :	22 4 2025 to 24 4 2025
📅 :	3 Days
📄 :	Other
🌐 :	https://www.scycle.info/
💰 :	US\$0.00
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🏢 :	United Nations Environment Programme (UNEP)



The United Nations Environment Programme (UNEP) project *Enhancing countries' capacities for measuring progress on the transition towards a circular economy* (running between 2024 and 2026), takes a multi-level approach to building global capacity around data and statistics on the circular economy, with a focus on:

1. Developing and strengthening statistical methodologies at the global level such as through the preparation of the third edition of the global *E-waste Statistics Guidelines*;
2. Supporting regional capacity building and dialogue between data users and producers; and
3. Enhancing, through tailored national activities, the technical capabilities of country-level institutions to regularly publish datasets on the circular economy and waste.



Electronic waste (e-waste) is a rapidly growing waste stream across many countries. Delivered as part of the UNEP project *Enhancing countries' capacities for measuring progress on the transition towards a circular economy*, the objective of the 2025 *International Workshop Series on E-waste Statistics* is to support relevant authorities across selected countries in developing the technical knowledge and capacities to regularly collect and publish statistics on e-waste. In addition, the workshop series provides a forum to further test changes proposed in the draft third edition of the global *E-waste Statistics Guidelines* prior to its final publication.



Through the workshop series, participants are sought to be equipped with the knowledge and capabilities to:

- Describe key concepts relating to monitoring e-waste and its relevance as part of tracking progress against the SDGs, particularly SDGs 11.6.1, 12.4.2a, 12.4.2b
- Explain how selected waste indicators are calculated alongside relevant data sources, and be able to use United Nations Institute for Training and Research (UNITAR) tools to produce statistics on e-waste; and
- Tackle challenges countries may be facing in compiling statistics on e-waste and actions and strategies that can be taken to address these as part of a national statistics implementation plan.



The workshop was made up of the following modules: Module 1. General introductions to the selected waste stream and its relation to the SDGs; Module 2. Waste statistics guidelines (classifications and mass balance principles); Module 3. How to use existing and tailored statistical toolkits and available core data sets; Module 4. Developing national statistics implementation plan; Session 5. How to integrate the developed waste statistics for ongoing production and decision making



Across the three days, calculation methods and data sources for the following variables across the life cycle of electronics were covered:

- Electrical and Electronic Equipment (EEE) placed on the market (POM);
- E-waste generated;
- The environmentally sound management (ESM) of e-waste (formal collection and treatment);
- Other e-waste disposal; and
- Transboundary movement of used EEE and e-waste.

The workshop is being followed by 10 days of remote training and engagement, as national officers progress in further developing statistics on e-waste, reporting on relevant SDG indicators, and as part of producing a National E-waste Monitor.



The target audience for the workshop series is representatives from country National Statistical Offices (NSOs) and ministries involved in the production of statistics on the environment (e.g., Environment, Industry and Economy), particularly those relating to resources and waste. In addition, bodies with an interest across the life cycle of electronics, including (the regulation of) imports, exports and domestic production of electronic goods, ICT and telecommunications, and the management of e-waste and waste more generally.